

**Sharad C. Seth**  
(Curriculum Vitae)

1971 Sewell Street  
Lincoln, NE 68502

*Email:* sesh@cse.unl.edu  
*Web:* <http://cse.unl.edu/~sesh>  
*Telephone:* (402) 472-5003 (W)  
475-7978 (H)

Professor of Computer Science & Engineering  
University of Nebraska-Lincoln

### Education

B.E.(Hons.)	Electronics & Telecommunications	1964	Jabalpur, India
M.Tech	Electrical Engineering	1966	I.I.T. Kanpur, India
Ph.D.	Electrical Engineering	1970	U. of Illinois, Urbana-Champaign

### Professional Experience

1983 – present, University of Nebraska-Lincoln, Professor, Computer Science & Engineering

1996 – 2003, University of Nebraska-Lincoln, Director, Center for Communication and Information Science (CCIS), Interim during the first year

1998 –2003, University of Nebraska-Lincoln, Coordinator, Research Computing Facility (RCF)

1976 – 1983, University of Nebraska-Lincoln, Associate Professor, Computer Science

1970 – 1976, University of Nebraska-Lincoln, Assistant Professor, Computer Science

**Professional Societies:** IEEE (Fellow), ACM (Member), VLSI Society of India (Member)

### Research

#### VLSI Testing

Test and Test-point selection in high-volume manufacturing [*ISQED*:236-241 2008, *VTS*:318-324 2007]

Low -power Testing and Test Compaction [*ISCAS'2010*: (Schemm et al.), *VTS'2010*: 307-312, *VDC'2010*: 9-14, *Fundamenta Informaticae*: 2008, *VDC'2005*:491-496, *ATS*:337-342 2005, *ITC*:470-479 2003, *TC* 33(10):934-937 1984]

Random-Pattern Testability and Testability Analysis [*JETTA* 19(3):271-284 2003, *TC* 39(11):582-586 1990, *Integration* 7(1):49-75 1989, *TC* 38(11):1558-1563 1989, *ETC*:139-143 1989, *DFT*:47-52 1988, *FTCS*:318-323 1986, *FTCS*:220-225 1985, *ICCD*:562-656 1985, *ISCAS*:687-690 1985, *ITC*:803-805 1985]

Determining Product Quality from Test Data [TVLSI 1(4):537-545 1993, ITC:712-720 1990, TCAD 3(4):123-126 1986, JSCC SC17:57-61 1981, EDL 2(11):286-287 1981, DAC: 196-203 1981]

### **Document Image Analysis**

Web Table Analysis [ICDAR'2011 242-246, IEA/AIE'2011–LNAI6703 253-263, DAS'2010:81-88, MKM'2009–LNCS5625: 422-437, GREC'2009: 25-36]

Handwriting and Character Recognition [LNCS 4768: 218-230 2008, ICPR:99-103 2006, SPIE 5296:102-108 2003, PAMI 9(5):710-715 1987, ICPR:352-355 1986]

XY-Tree Sementation [ICDAR:827-831 2001, ICDAR:615-618 1995, Library Hi Tech 11(3):73-92 1993, PAMI 15(7):737-747 1993, IEEE Computer 25(7):10-22 1992, Pattern Recognition in Practice II:149-159 1986, ICPR:347-349 1984]

Map Image Understanding [JJDAR 2(4):177-185 2000, LNCS 1389K:302-313 1998, ICDAR:467-470 1999, GREC:268-276 1997, GIS/LIS:89-97 1997]

### **Honors and Awards**

IEEE Fellow Award “For contributions to testing of digital electronics circuits”, 1997.

Best Poster Paper Award, 3<sup>rd</sup> *International Conference on Document Analysis and Recognition*, 1995.

Honorable Mention Paper Award, *International Conference on VLSI Design*, 1992.

Best Paper Award, Design and Test Category, *International Conference on Computer Design*, 1988.

Best Presentation Paper Award, *International Conference on Computer Design*, 1985.

### **Teaching**

#### **Frequently Taught Courses**

Computer Organization, VLSI Design, Microcomputer Applications, Computer Architecture, Professional Development, Senior Design, Fault Tolerant Computing (VLSI Testing)

*Organizer and Speaker*: Tutorial on “Test Generation for VLSI Circuits”, International Test Conference (1987, 88, 89, 90), Design Automation Conference (1989), First European Test Conference (1989), VLSI Design Conference (1992 and 95).

**Direction of Graduate Student Research as Major Advisor**: 11 PhD and 25 Masters students.

### **Significant Professional Service**

JETTA Editorial Board: 1990 – present; *IEEE Transactions on Computer Aided Design*: Associate Editor 1989-1992; *IEEE Design & Test of Computers*: Editor of Tutorials and Short Papers, 1987-1991; *EIT 2005*: Program Committee Chair;